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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	70
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-pl84i

Device/Package	Speed Grade ¹				Application ¹			
	Std.	–1	–2	–3	C	I	M	B
A14V40A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
A1460A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–
196-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
207-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
208-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	–	–	–
A14V60A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
208-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A14100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	✓	D	D	✓	✓	–	–
257-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
313-Pin Plastic Ball Grid Array (BGA)	✓	✓	D	D	✓	–	–	–
256-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
A14V100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	–	–	–	✓	–	–	–
313-Pin Plastic Ball Grid Array (BGA)	✓	–	–	–	✓	–	–	–

Notes:

- Applications:**
C = Commercial
I = Industrial
M = Military
2. Commercial only

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

1 – ACT 3 Family Overview

General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

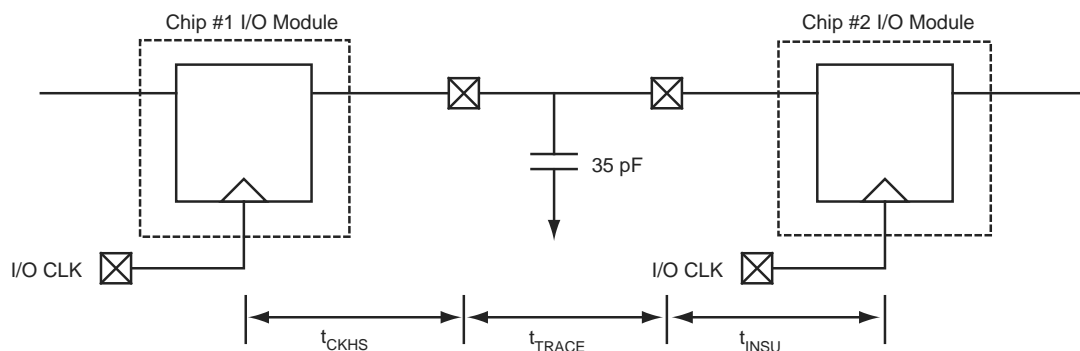
The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

Accumulators (16-Bit)	47 MHz
Loadable Counters (16-Bit)	82 MHz
Prescaled Loadable Counters (16-Bit)	186 MHz
Shift Registers	186 MHz

Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade)

System Performance Model



Module Output Connections

Module outputs have dedicated output segments. Output segments extend vertically two channels above and two channels below, except at the top or bottom of the array. Output segments twist, as shown in Figure 10, so that only four vertical tracks are required.

LVT Connections

Outputs may also connect to nondedicated segments called Long Vertical Tracks (LVTs). Each module pair in the array shares four LVTs that span the length of the column. Any module in the column pair can connect to one of the LVTs in the column using an FF connection. The FF connection uses antifuses connected directly to the driver stage of the module output, bypassing the isolation transistor. FF antifuses are programmed at a higher current level than HF, VF, or XF antifuses to produce a lower resistance value.

Antifuse Connections

In general every intersection of a vertical segment and a horizontal segment contains an unprogrammed antifuse (XF-type). One exception is in the case of the clock networks.

Clock Connections

To minimize loading on the clock networks, a subset of inputs has antifuses on the clock tracks. Only a few of the C-module and S-module inputs can be connected to the clock networks. To further reduce loading on the clock network, only a subset of the horizontal routing tracks can connect to the clock inputs of the S-module.

Programming and Test Circuits

The array of logic and I/O modules is surrounded by test and programming circuits controlled by the temporary special I/O pins MODE, SDI, and DCLK. The function of these pins is similar to all ACT family devices. The ACT 3 family also includes support for two Actionprobe[®] circuits, allowing complete observability of any logic or I/O module in the array using the temporary special I/O pins, PRA and PRB.

Package Thermal Characteristics

The device junction to case thermal characteristic is θ_{jc} , and the junction to ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a CPGA 175-pin package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. (°C)} - \text{Max. ambient temp. (°C)}}{\theta_{ja} \text{ °C/W}} = \frac{150^{\circ}\text{C} - 70^{\circ}\text{C}}{25^{\circ}\text{C/W}} = 3.2 \text{ W}$$

EQ 2

Table 2-8 • Package Thermal Characteristics

Package Type*	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft./min.	Units
Ceramic Pin Grid Array	100	20	35	17	°C/W
	133	20	30	15	°C/W
	175	20	25	14	°C/W
	207	20	22	13	°C/W
	257	20	15	8	°C/W
Ceramic Quad Flatpack	132	13	55	30	°C/W
	196	13	36	24	°C/W
	256	13	30	18	°C/W
Plastic Quad Flatpack	100	13	51	40	°C/W
	160	10	33	26	°C/W
	208	10	33	26	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	11	32	25	°C/W
Power Quad Flatpack	208	0.4	17	13	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Plastic Ball Grid Array	225	10	25	19	°C/W
	313	10	23	17	°C/W

Note: Maximum power dissipation in still air:

PQ160 = 2.4 W

PQ208 = 2.4 W

PQ100 = 1.6 W

VQ100 = 1.9 W

TQ176 = 2.5 W

PL84 = 2.2 W

RQ208 = 4.7 W

BG225 = 3.2 W

BG313 = 3.5 W

Tightest Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer lengths of routing track. The ACT 3 family delivers the tightest fanout delay distribution of any FPGA. This tight distribution is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented PLICE antifuse offers a very low resistive/capacitive interconnect. The ACT 3 family's antifuses, fabricated in 0.8 micron m lithography, offer nominal levels of 200Ω resistance and 6 femtofarad (fF) capacitance per antifuse. The ACT 3 fanout distribution is also tighter than alternative devices due to the low number of antifuses required per interconnect path. The ACT 3 family's proprietary architecture limits the number of antifuses per path to only four, with 90% of interconnects using only two antifuses.

The ACT 3 family's tight fanout delay distribution offers an FPGA design environment in which fanout can be traded for the increased performance of reduced logic level designs. This also simplifies performance estimates when designing with ACT 3 devices.

Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions

Speed Grade	FO = 1	FO = 2	FO = 3	FO = 4	FO = 8
ACT 3 –3	2.9	3.2	3.4	3.7	4.8
ACT 3 –2	3.3	3.7	3.9	4.2	5.5
ACT 3 –1	3.7	4.2	4.4	4.8	6.2
ACT 3 STD	4.3	4.8	5.1	5.5	7.2

Notes:

1. Obtained by added $t_{RD(x=FO)}$ to t_{PD} from the Logic Module Timing Characteristics Tables found in this datasheet.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

Timing Characteristics

Timing characteristics for ACT 3 devices fall into three categories: family dependent, device dependent, and design dependent. The input and output buffer characteristics are common to all ACT 3 family members. Internal routing delays are device dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the ALS Timer utility or performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically up to 6% of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 14 ns delay. This additional delay is represented statistically in higher fanout (FO = 8) routing delays in the datasheet specifications section.

A1460A, A14V60A Timing Characteristics (continued)

Table 2-33 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{IOCKH}	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t _{IOPWH}	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t _{IPOWL}	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{IOCKSW}	Maximum Skew		0.6		0.6		0.6		0.6		0.6	ns
t _{IOP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{IOMAX}	Maximum Frequency		200		150		125		100		75	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HPWH}	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t _{HPWL}	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.6		0.6		0.6		0.6		0.6	ns
t _{HP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{HMAX}	Maximum Frequency		200		150		125		100		75	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RCKL}	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RCKSW}	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t _{RP}	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f _{RMAX}	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.7	0.0	1.7	0.0	1.7	0.0	1.7	0.0	5.0	ns
		0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.3	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

A14100A, A14V100A Timing Characteristics

Table 2-34 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing ¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A14100A, A14V100A Timing Characteristics (continued)

Table 2-37 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

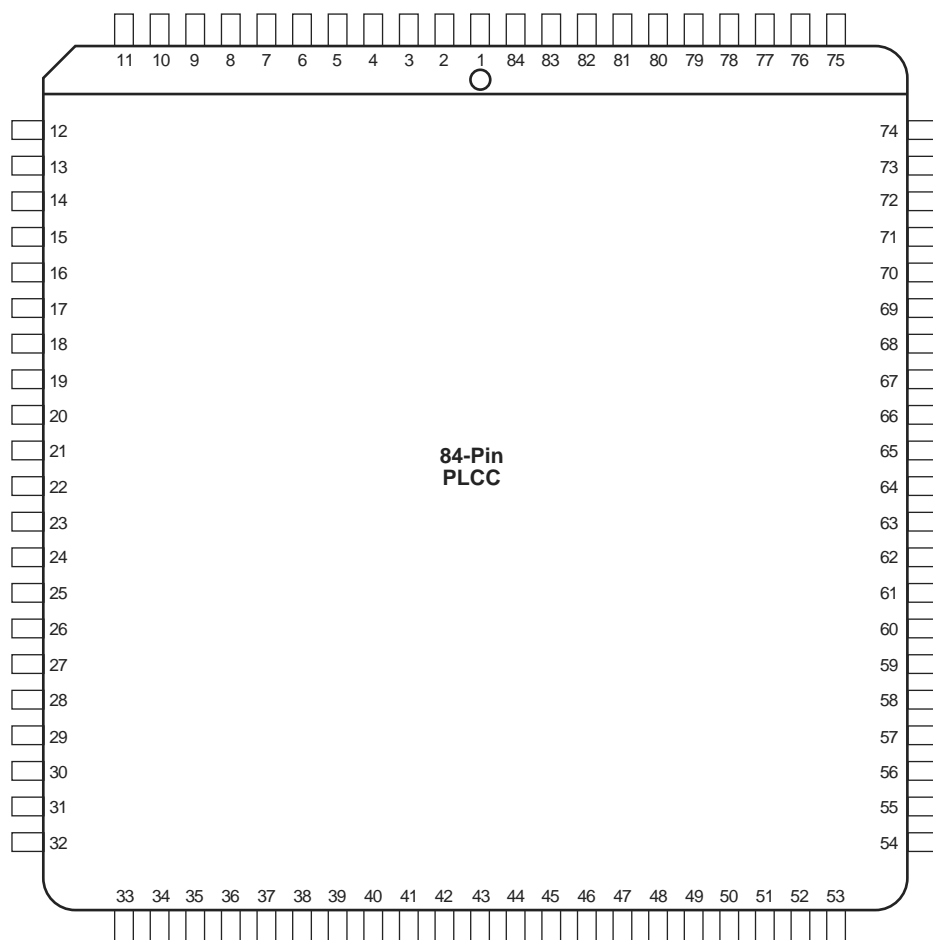
Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t _{IOPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t _{IPOWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	2.4		3.3		3.8		4.8		6.5		ns
t _{ILOCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		0.6	ns
t _{IOP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{IOMAX}	Maximum Frequency		200		150		125		100		75	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t _{HPWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.6		0.6		0.7		0.8		0.6	ns
t _{HP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{HMAX}	Maximum Frequency		200		150		125		100		75	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RCKL}	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RCKSW}	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t _{RP}	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f _{RMAX}	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0	1.7	0.0	1.7	0.0	1.7	0.0	1.7	0.0	5.0	ns
		0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0	1.3	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes: *

- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
- Delays based on 35 pF loading.

3 – Package Pin Assignments

PL84



Note: This is the top view of the package.

Note

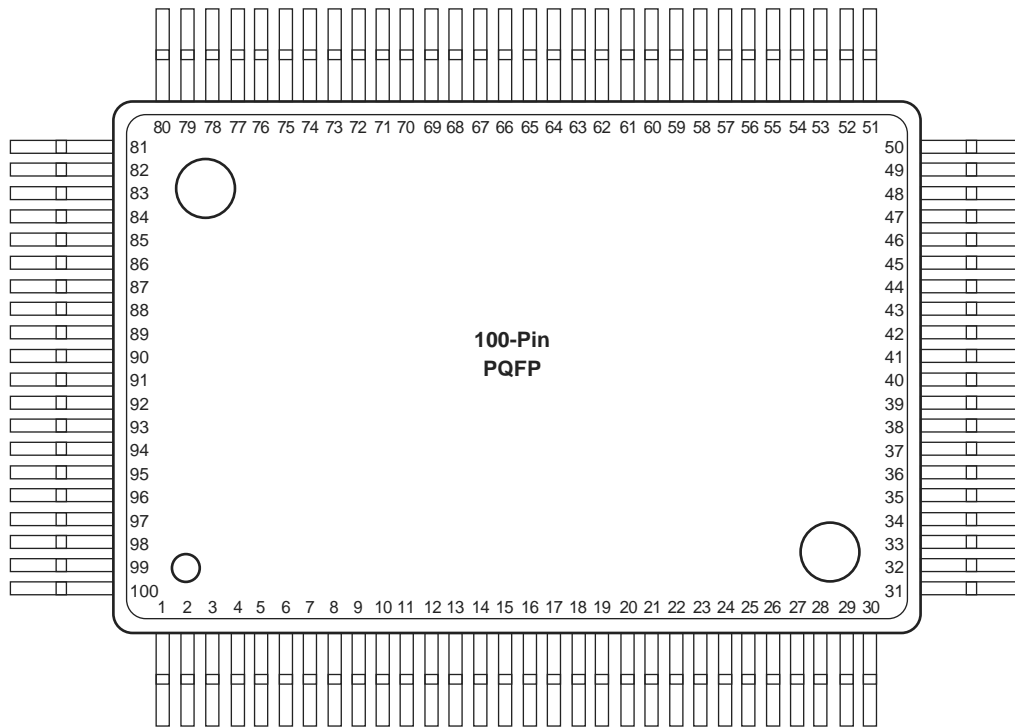
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

PL84			
Pin Number	A1415, A14V15 Function	A1425, A14V25 Function	A1440, A14V40 Function
1	VCC	VCC	VCC
2	GND	GND	GND
3	VCC	VCC	VCC
4	PRA, I/O	PRA, I/O	PRA, I/O
11	DCLK, I/O	DCLK, I/O	DCLK, I/O
12	SDI, I/O	SDI, I/O	SDI, I/O
16	MODE	MODE	MODE
27	GND	GND	GND
28	VCC	VCC	VCC
40	PRB, I/O	PRB, I/O	PRB, I/O
41	VCC	VCC	VCC
42	GND	GND	GND
43	VCC	VCC	VCC
45	HCLK, I/O	HCLK, I/O	HCLK, I/O
52	SDO	SDO	SDO
53	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
59	VCC	VCC	VCC
60	VCC	VCC	VCC
61	GND	GND	GND
68	VCC	VCC	VCC
69	GND	GND	GND
74	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
83	CLKA, I/O	CLKA, I/O	CLKA, I/O
84	CLKB, I/O	CLKB, I/O	CLKB, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ100



Note: This is the top view of the package.

Note

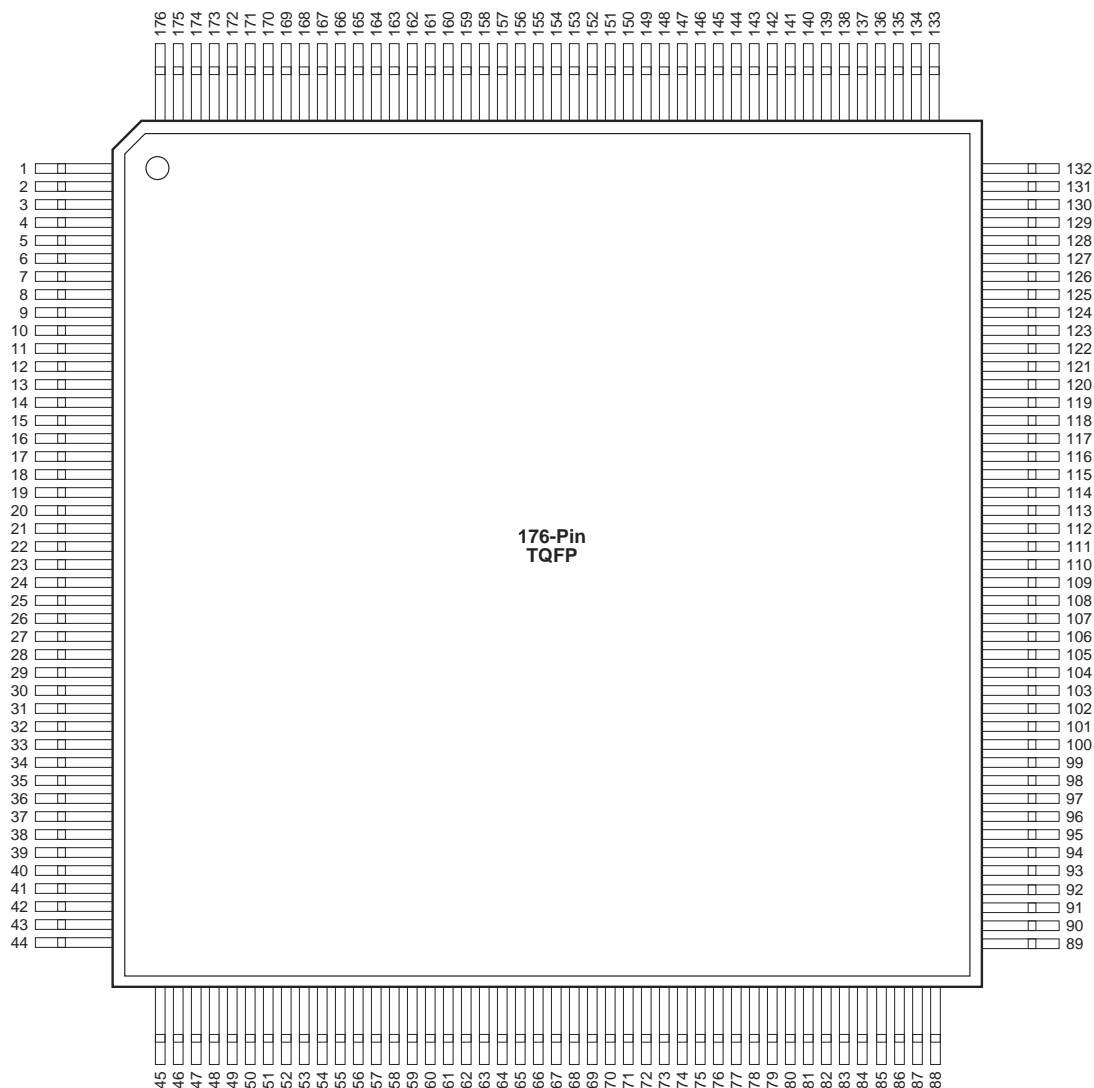
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PQ160			
Pin Number	A1425, A14V25 Function	A1440, A14V40 Function	A1460, A14V60 Function
92	NC	I/O	I/O
93	NC	I/O	I/O
98	GND	GND	GND
99	VCC	VCC	VCC
100	NC	I/O	I/O
103	GND	GND	GND
107	NC	I/O	I/O
109	NC	I/O	I/O
110	VCC	VCC	VCC
111	GND	GND	GND
112	VCC	VCC	VCC
113	NC	I/O	I/O
119	NC	I/O	I/O
120	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
121	GND	GND	GND
124	NC	I/O	I/O
127	NC	I/O	I/O
136	CLKA, I/O	CLKA, I/O	CLKA, I/O
137	CLKB, I/O	CLKB, I/O	CLKB, I/O
138	VCC	VCC	VCC
139	GND	GND	GND
140	VCC	VCC	VCC
141	GND	GND	GND
142	PRA, I/O	PRA, I/O	PRA, I/O
143	NC	I/O	I/O
145	NC	I/O	I/O
147	NC	I/O	I/O
149	NC	I/O	I/O
151	NC	I/O	I/O
153	NC	I/O	I/O
154	VCC	VCC	VCC
160	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

TQ176



Note: This is the top view.

Note

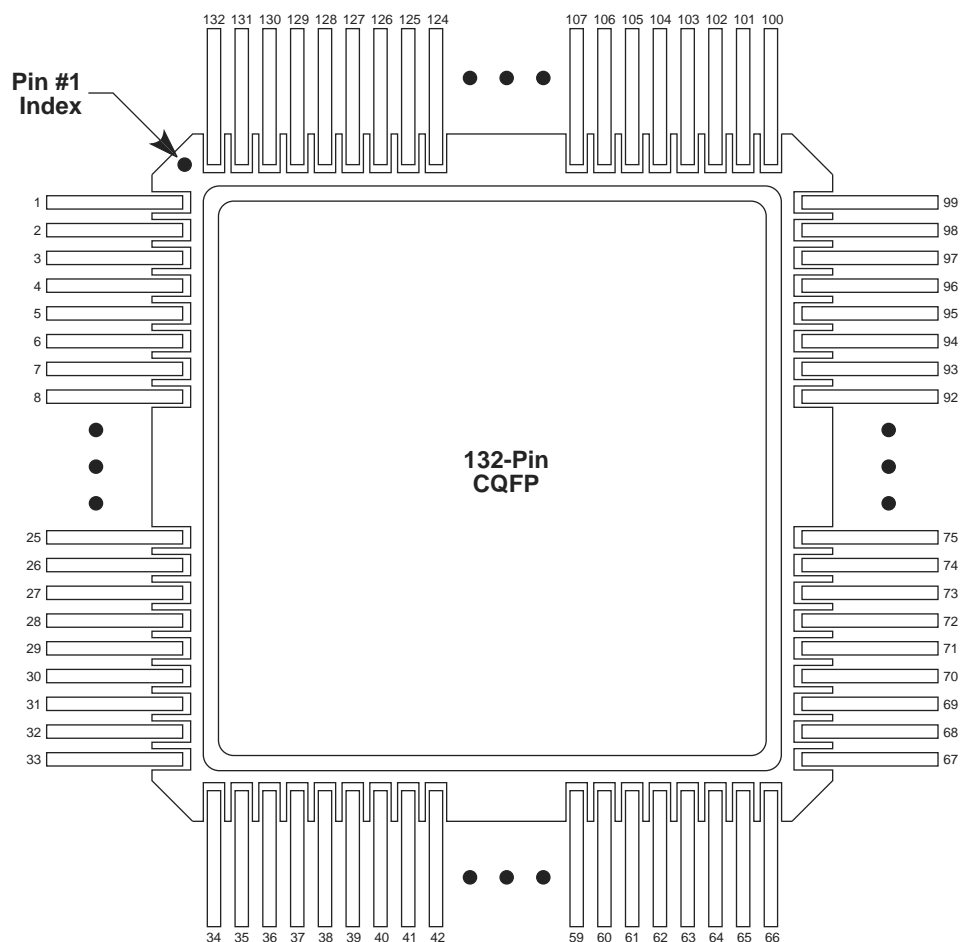
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

TQ176			TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function	Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
1	GND	GND	89	GND	GND
2	SDI, I/O	SDI, I/O	98	VCC	VCC
10	MODE	MODE	99	VCC	VCC
11	VCC	VCC	108	GND	GND
20	NC	I/O	109	VCC	VCC
21	GND	GND	110	GND	GND
22	VCC	VCC	119	NC	I/O
23	GND	GND	121	NC	I/O
32	VCC	VCC	122	VCC	VCC
33	VCC	VCC	123	GND	GND
44	GND	GND	124	VCC	VCC
49	NC	I/O	132	IOCLK, I/O	IOCLK, I/O
51	NC	I/O	133	GND	GND
63	NC	I/O	138	NC	I/O
64	PRB, I/O	PRB, I/O	152	CLKA, I/O	CLKA, I/O
65	GND	GND	153	CLKB, I/O	CLKB, I/O
66	VCC	VCC	154	VCC	VCC
67	VCC	VCC	155	GND	GND
69	HCLK, I/O	HCLK, I/O	156	VCC	VCC
82	NC	I/O	157	PRA, I/O	PRA, I/O
83	NC	I/O	158	NC	I/O
87	SDO	SDO	170	NC	I/O
88	IOPCL, I/O	IOPCL, I/O	176	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ132



Note: This is the top view

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

CQ132	
Pin Number	A1425 Function
1	NC
2	GND
3	SDI, I/O
9	MODE
10	GND
11	VCC
22	VCC
26	GND
27	VCC
34	NC
36	GND
42	GND
43	VCC
48	PRB, I/O
50	HCLK, I/O
58	GND
59	VCC
63	SDO
64	IOPCL, I/O
65	GND
66	NC

CQ132	
Pin Number	A1425 Function
67	NC
74	GND
75	VCC
78	VCC
89	VCC
90	GND
91	VCC
92	GND
98	IOCLK, I/O
99	NC
100	NC
101	GND
106	GND
107	VCC
116	CLKA, I/O
117	CLKB, I/O
118	PRA, I/O
122	GND
123	VCC
131	DCLK, I/O
132	NC

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

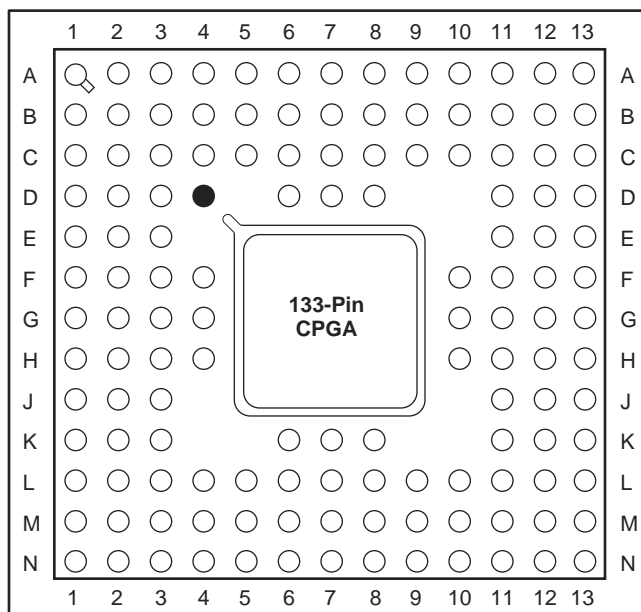
CQ256	
Pin Number	A14100 Function
1	GND
2	SDI, I/O
11	MODE
28	VCC
29	GND
30	VCC
31	GND
46	VCC
59	GND
90	PRB, I/O
91	GND
92	VCC
93	GND
94	VCC
96	HCLK, I/O
110	GND
126	SDO
127	IOPCL, I/O
128	GND

CQ256	
Pin Number	A14100 Function
141	VCC
158	GND
159	VCC
160	GND
161	VCC
174	VCC
175	GND
176	GND
188	IOCLK, I/O
189	GND
219	CLKA, I/O
220	CLKB, I/O
221	VCC
222	GND
223	VCC
224	GND
225	PRA, I/O
240	GND
256	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG133



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG175	
A1440 Function	Location
CLKA or I/O	C9
CLKB or I/O	A9
DCLK or I/O	D5
GND	D4, D8, D11, D12, E4, E14, H4, H12, L4, L12, M4, M8, M12
HCLK or I/O	R8
IOCLK or I/O	E12
IOPCL or I/O	P13
MODE	F3
NC	A1, A2, A15, B2, B3, P2, P14, R1, R2, R14, R15
PRA or I/O	B8
PRB or I/O	R7
SDI or I/O	D3
SDO	N12
VCC	C3, C8, C13, E15, H3, H13, L1, L14, N3, N8, N13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG175 package has been discontinued.